Application/Control No. Applicant(s)/Patent Under Reexamination 10/626,610 ASANO ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Matthew B. Smithers 2137 **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY US-2005/0094848 05-2005 Carr et al. 382/100 US-7 130 443 10-2006 Worner et al 292/100

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